

FPD Materials & Components Japan TC Chapter

Meeting Summary and Minutes

Wednesday, January 25, 2023, 15:00-17:00(JST) OVTCCM / SEMI Japan office, Tokyo, Japan. (Hybrid)

TC Chapter Announcements

Next TC Chapter Meeting

FPD Materials & Components and FPD Metrology Japan Joint TC Chapter

Friday, June 2, 2023, 14:30-17:00[JST]

OVTCCM / SEMI Japan office, Tokyo, Japan. (Hybrid)

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chair: Tadahiro Furukawa (Yamagata University), Ryoichi Watanabe (Japan Display), Toshimasa Eguchi (Sumitomo Bakelite)

SEMI Staff: Nobuko Okayasu (SEMI Japan), Mami Nakajo (SEMI Japan)

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Company	Last	First	Company	Last	First
Yamagata University	Furukawa	Tadahiro	НОҮА	Kondo	Keitaro
FUJIFILM	Ishizuka	Hiroshi	Sumitomo Bakelite	Eguchi	Toshimasa
Japan Display	Watanabe	Ryoichi	NIPPON STEEL Chemical &Material	Nakatsuka	Jun
Teijin	Itoh	Haruhiko	SK-Electronics	Miyazaki	Shohei
MORESCO	Uehigashi	Atsushi	SEMI Japan	Yoshida	Akiko
SEMI Japan	Okayasu	Nobuko	SEMI Japan	Nakajo	Mami

Table 2 Leadership Changes

WG/TF/SC/TC Name	Previous Leader	New Leader	
None			

Table 3 Committee Structure Changes

Previous WG/TF/SC Name	New WG/TF/SC Name or Status Change	
None		

Table 4 Ballot Results

Document #	Document Title	Committee Action
None		

^{#1} Passed ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

^{#2} Failed ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.



Table 5 Activities Approved by the GCS between meetings of the TC Chapter

#	Туре	SC/TF/WG	Details
None			

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

#	Туре	SC/TF/WG	Details
None			

^{#1} SNARFs and TFOFs are available for review on the SEMI Web site at:

http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF

Table 7 Authorized Ballots

#	When	TF	Details
6977		FPD Materials & Components Maintenance TF	Line Item Revision to SEMI D34-0710: "TEST METHOD FOR FPD POLARIZING FILMS"

Table 8 SNARF(s) Granted a One-Year Extension

#	TF	Title	Expiration Date
None			

Table 9 SNARF(s) Abolished

	#	TF	Title
N	lone		

Table 10 Standard(s) to receive Inactive Status

Standard Designation	Title
None	

Table 11 New Action Items

Item #	Assigned to	Details
20230125-01	Tadahiro Furukawa	To review SEMI D63-0818-EN for 5year review by next TC
	FPD Materials & Components Flexible Display Task Force	To review the documents according to the 5year review list To prepare the SNARF for Line Item RevisionD78 by next TC

Table 12 Previous Meeting Action Items

Item #	Assigned to	Details
20221014-01	Mami Nakajo	To send the ballot review sheets to the A&R
	(SEMI Japan)	>Completed



		To prepare the Document #6977, Line Item Revision to SEMI D34-0710: "TEST	
	Components Maintenance Task Force	METHOD FOR FPD POLARIZING FILMS" by the next TC Chapter Meeting >Completed	

1. Welcome, Reminders, and Introductions

Toshimasa Eguchi (Sumitomo Bakelite) called the meeting to order at 14:30. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: 01-01_RequiredElementNov2020Rev1-E&J-r1

2. Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Approved on condition that the modifications are changed.

Motion:	Approve the previous meeting minutes as written	
By / 2 nd :	Ryoichi Watanabe (Japan Display), Jun Nakatsuka (NIPPON STEEL Chemical & Material)	
Discussion:	None	
Vote:	8-0, motion passed	

Attachment: 02-01 20221014 FPD-MC Japan MeetingMinutes

3. Technical Committee Awards

the following member received the awards for Individuals involved in leading documentation development for the first time (Doc.6937 TERMINOLOGY FOR FPD PHASE SHIFT MASK AND MASK BLANKS).

Shohei Miyazaki SK-Electronics CO., LTD

Keitaro Kondo HOYA Corporation

4. Liaison Reports

4.1 FPD Metrology Korea TC Chapter

Nobuko Okayasu (SEMI Japan) reported for the FPD Metrology Korea TC Chapter as attached material.

Attachment: 04-01_Liaison report_FPDM_KR_June2022

4.2 FPD Metrology Taiwan TC Chapter

Nobuko Okayasu (SEMI Japan) reported for the FPD Metrology Taiwan TC Chapter as attached material.

Attachment: 04-02_FPD-M TW Liaison Report_20221031_v1

5. SEMI Staff Report

5.1 Nobuko Okayasu (SEMI Japan) gave the SEMI Staff Report.

Attachment: 05-01_Staff Report Nov 2022 v5 (1)+J+HQDec2022



6. Ballot Review

6.1 None

7. Subcommittee and Task Force Reports

7.1 <Flexible Display Task Force>

Tadahiro Furukawa (Yamagata University) reported for the task force that the 5year review will be implemented and that the SNARF of Line Item Revision D78 will be prepared by the next TC.

7.2 <FPD Mask Task Force>

Keitaro Kondo (HOYA) reported that a meeting is to be held on March 14.

7.3 <FPD Materials & Components Maintenance Task Force>

Hiroshi Ishizuka (FUJIFILM) reported for the task force as attached. Furthermore, he requested to approve to submit the Document for Line Item Revision to SEMI D39-0704 (Reapproved 0117): "SPECIFICATION FOR MARKERS ON FPD POLARIZING FILMS" to Letter Ballot Cycle2 or 3.

Approved on condition that the Document will be submitted.

Motion:	: Authorized document for letter ballot, SEMI Draft Document 6977		
	Line Item Revision to SEMI D34-0710 (Reapproved 0117):		
	"TEST METHOD FOR FPD POLARIZING FILMS" for Cycle 2 or 3		
By / 2 nd :	Hiroshi Ishizuka (FUJIFILM Corporation), Tadahiro Furukawa (Yamagata University)		
Discussion:	None		
Vote:	8-0, motion passed		

Attachment: 07-03_20230125Maintenance TF report_r

8. Old Business

8.1 Project period Review - None

8.2 5-year Review Check

Nobuko Okayasu (SEMI Japan) reported that there are the following documents at this moment.

- SEMI D78-1018, Test Method of Water Vapor Barrier Property for Plastic Films with High Barrier for Electronic Devices
- SEMI D77-0618, Test Method for Measurements of Dimension of Films for FPD Contour Matching Method
- SEMI D63-0818, Test Method for Depolarization Effect of FPD Color Filter
- SEMI D60-0818, Test Method of Surface Scratch Resistance for FPD Polarizing Film and Its Materials
- SEMI D6-0211 (Reapproved 0117), Specification for Liquid Crystal Display (LCD) Mask Substrates
- SEMI D39-0704 (Reapproved 0117), Specification for Markers on FPD Polarizing Films
- SEMI D38-0211 (Reapproved 0117), Guide for Quality Area of LCD Masks
- SEMI D34-0710 (Reapproved 0117), Test Method for FPD Polarizing Films

Attachment: 08-02 5YearReview FPDMC



9. New Business

9.1 Project Period Review - None

10. Action Item Review

10.1 Open Action Items - None

10.2New Action Items

The TC Chapter reviewed the following items.

Item #	Assigned to	Details
20230125-01	Tadahiro Furukawa	To review SEMI D63-0818-EN for 5year review by next TC
		To review the documents according to the 5year review list To prepare the SNARF for Line Item RevisionD78 by next TC

11. Next Meeting and Adjournment

The next FPD Materials & Components and FPD Meteorology Japan TC Chapter joint meeting is scheduled as follows:

Date: Friday, June 2, 2023, Time: 14:30-17:00[JST]

Place: OVTCCM / SEMI Japan office, Tokyo, Japan. (Hybrid)

See http://www.semi.org/en/events for the current list of meeting schedules.

Adjournment: [16:50]>.

Respectfully submitted by:

Nobuko Okayasu Standards & EHS SEMI Japan

Phone: 81.3.3222.2022 Email: nokayasu@semi.org

Minutes tentatively approved by:

Tadahiro Furukawa (Yamagata University), Co-chair	
Ryoichi Watanabe (Japan Display), Co-chair	
Toshimasa Eguchi (Sumitomo Bakelite), Co-chair	

Table 13 Index of Available Attachments#1

Title	Title
01-01_RequiredElementNov2020Rev1-E&J-r1	05-01_Staff Report Nov 2022 v5 (1)+J+HQDec2022
02-01_20221014_FPD-MC_Japan_MeetingMinutes	07-03_20230125Maintenance TF report_r
04-01_Liaison report_FPDM_KR_June2022	08-02_5YearReview_FPDMC



Table 13 Index of Available Attachments#1

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Nobuko Okayasu at the contact information above.